

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S23	2	("5652182").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/29 12:41
S22	2	("5710061").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/29 12:41
S21	130	air adj gap near semiconductor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/29 12:41
S24	210424	air adj (bridge or pocket or space or gap)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/29 12:42
S17	4481003	air adj bridge or pocket or space or gap	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/29 12:42
S26	605	air adj gap near dielectric	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/05/29 12:43

## EAST Search History

S25	6	air adj gap near metal adj line	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/29 12:43
S4	2	("6946382").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2007/05/29 12:52
S28	2801	430/313.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/29 12:53
S27	1896	430/394.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/29 12:53
S34	1	S29 and S32	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/29 13:10
S33	9832	IMD	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/29 13:10
S32	2812	inter adj metal adj dielectric	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/29 13:10

## EAST Search History

S31	1	S29 and S30	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/29 13:10
S30	2821	inter near metal near dielectric	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/29 13:10
S35	3	S29 and S33	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/29 14:45
S38	1896	430/394.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/30 08:52
S37	5857	430/311	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/30 08:52
S29	182	S27 and S28	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/30 08:52
S39	392	S38 and S37	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/30 09:07

## EAST Search History

S42	2	("5559055").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2007/05/30 09:08
S41	2	("5869880").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2007/05/30 09:08
S40	2	("5461003").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2007/05/30 09:08
S19	577	air adj gap near dielectric	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/30 13:32
S46	219	S43 near S44	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/30 13:33
S45	7350	S43 same S44	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/30 13:33
S44	60387	wet adj etch\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/30 13:33

## EAST Search History

S43	118957	nitride adj (film or layer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	ON	2007/05/30 13:33
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